

Switching (30V, 7A)

RK9410

●Features

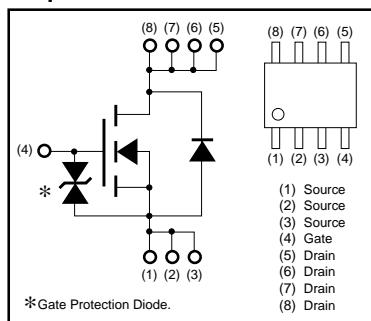
- 1) Low Qg.
- 2) Low on-resistance.
- 3) Excellent resistance to damage from static electricity.

●Structure

Silicon N-channel

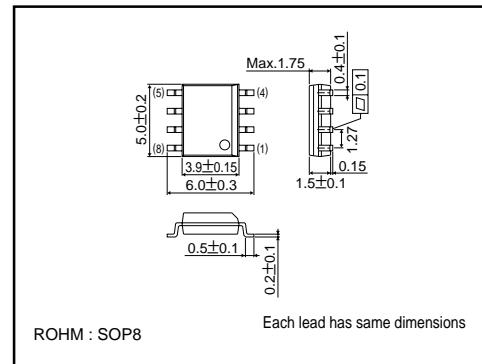
MOS FET

●Equivalent circuit



* A protection diode is included between the gate and the source terminals to protect the diode against static electricity when the product is in use. Use a protection circuit when the fixed voltage are exceeded.

●External dimensions (Units : mm)



●Absolute maximum ratings ($T_a=25^\circ\text{C}$)

Parameter	Symbol	Limits	Unit
Drain-Source Voltage	V_{DSS}	30	V
Gate-Source Voltage	V_{GSS}	± 20	V
Drain Current	Continuous	I_D	A
	Pulsed	I_{DP}^*	A
Reverse Drain Current	Continuous	I_{DR}	A
	Pulsed	I_{DRP}^*	A
Source Current (Body Diode)	Continuous	I_S	A
	Pulsed	I_{Sp}^*	A
Total Power Dissipation ($T_c=25^\circ\text{C}$)	P_D	2	W
Channel Temperature	T_{ch}	150	$^\circ\text{C}$
Storage Temperature	T_{stg}	-55~+150	$^\circ\text{C}$

* $P_w \leq 10\text{ms}$, Duty cycle $\leq 1\%$

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● Thermal resistance (Ta=25°C)

Parameter	Symbol	Limits	Unit
Channel to Ambient	R _{th(ch-A)}	62.5	°C / W

● Electrical characteristics (Ta=25°C)

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test Conditions
Gate-Source Leakage	I _{GSS}	—	—	±10	μA	V _{GS} =±20V, V _{DS} =0V
Drain-Source Breakdown Voltage	V _{(BR) DSS}	30	—	—	V	I _D =1mA, V _{GS} =0V
Zero Gate Voltage Drain Current	I _{DS}	—	—	1	μA	V _{DS} =30V, V _{GS} =0V
Gate Threshold Voltage	V _{GS(th)}	1.0	—	2.5	V	V _{DS} =10V, I _D =1mA
Static Drain-Source On-State Resistance	R _{DS(on)}	—	18	23	mΩ	I _D =7A, V _{GS} =10V
		—	28	37		I _D =7A, V _{GS} =4.5V
		—	33	43		I _D =7A, V _{GS} =4V
Forward Transfer Admittance	Y _{fs} *	5	—	—	S	I _D =7A, V _{DS} =10V
Input Capacitance	C _{iss}	—	710	—	pF	V _{DS} =10V
Output Capacitance	C _{oss}	—	400	—	pF	V _{GS} =0V
Reverse Transfer Capacitance	C _{rss}	—	200	—	pF	f=1MHz
Turn-On Delay Time	t _{d(on)*}	—	12	—	ns	I _D =3.5A, V _{DD} =15V
Rise Time	t _{r*}	—	43	—	ns	V _{GS} =10V
Turn-Off Delay Time	t _{d(off)*}	—	48	—	ns	R _L =4.3Ω
Fall Time	t _{f*}	—	30	—	ns	R _{GS} =10Ω
Total Gate Charge	Q _{g*}	—	20.5	41	nC	V _{DD} =15V
Gate-Source Charge	Q _{gs*}	—	3.3	—	nC	V _{GS} =10V
Gate-Drain Charge	Q _{gd*}	—	5.2	—	nC	I _D =7A

* Pulsed

● Body diode characteristics (Source-Drain Characteristics) (Ta=25°C)

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test Conditions
Forward Voltage	V _{SD*}	—	—	1.5	V	I _S =5.2A, V _{GS} =0V
Reverse Recovery Time	t _{rr*}	—	155	—	ns	I _{DR} =5.2A, V _{GS} =0V
Reverse Recovery Charge	Q _{rr*}	—	145	—	nC	di/dt=100A/μs

* Pulsed

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● Electrical characteristic curves

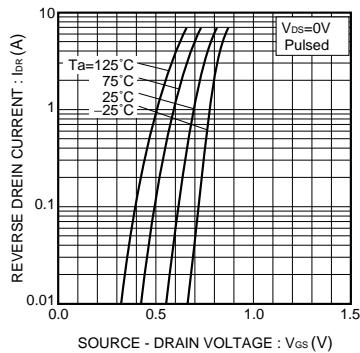


Fig.1 Reverse Drain Current vs. Source - Drain Voltage

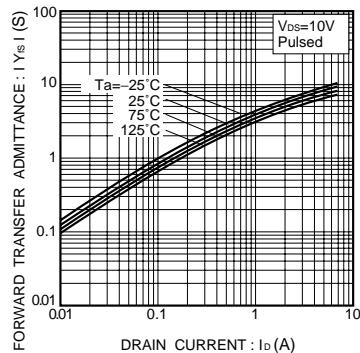


Fig.2 Forward Transfer Admittance vs. Drain Current

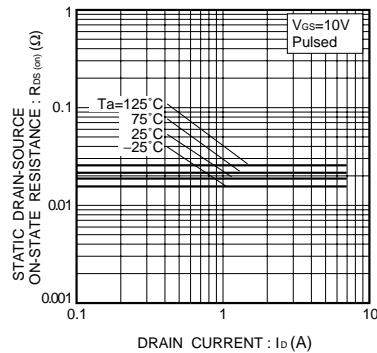
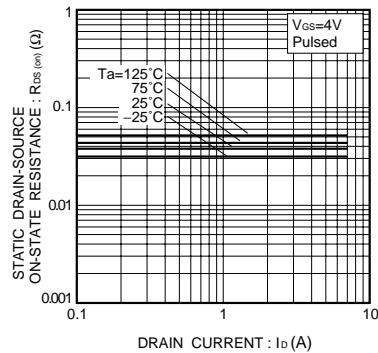
Fig.3 Static Drain-Source On-State Resistance vs. Drain Current (I)

Fig.4 Static Drain-Source On-State Resistance vs. Drain Current (II)

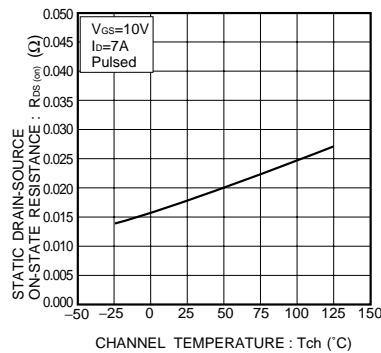


Fig.5 Static Drain-Source On-State Resistance vs. Channel Temperature

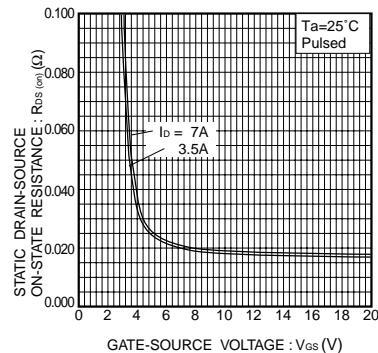


Fig.6 Static Drain-Source On-State Resistance vs. Gate-Source Voltage

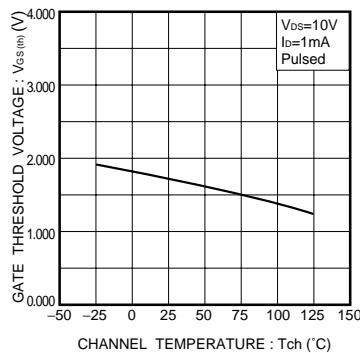


Fig.7 Gate Threshold Voltage vs. Channel Temperature

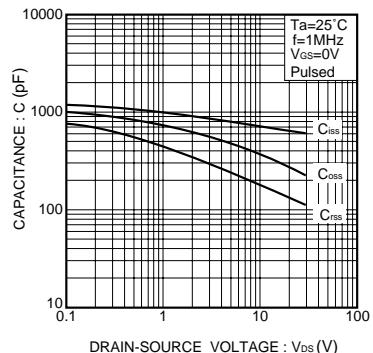


Fig.8 Typical Capacitance vs. Drain-Source Voltage

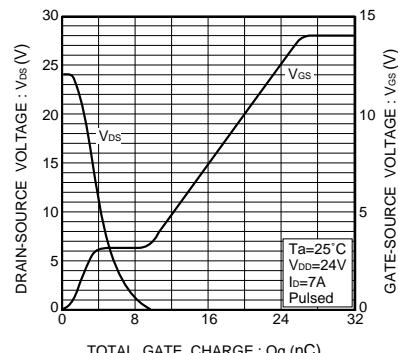


Fig.9 Dynamic Input Characteristics

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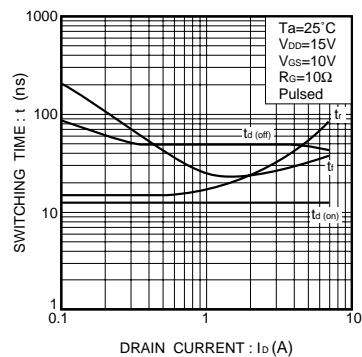


Fig.10 Switching Characteristics

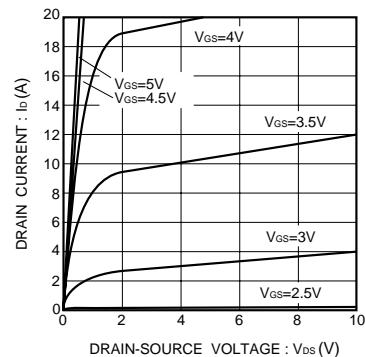


Fig.11 Typical Output Characteristics

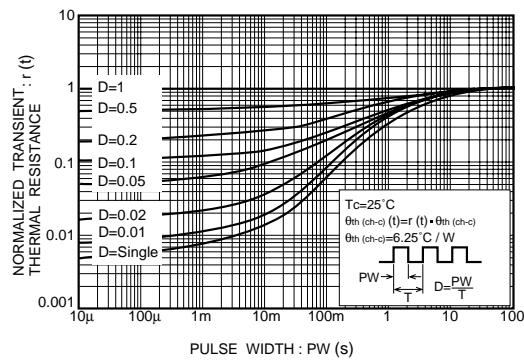


Fig.12 Normalized Transient Thermal Resistance vs. Pulse Width